

<b>INFORMATION DISCLOSURE CITATION</b> (Use several sheets if necessary)				Docket Number (Optional) <b>T36-163905M/KOH</b>		Application Number <b>Not Yet Assigned</b>	
				Applicant(s) <b>Shibata, et al.</b>			
				Filing Date <b>Concurrently Herewith</b>		Group Art Unit <b>Unknown</b>	

  

U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
DV		5,278,433	01/1994	Manabe, et al.			/
		4,153,905	05/1979	Charmakadze, et al.			/
		5,237,182	08/1992	Kitagawa, et al.			/
		4,855,249	08/1989	Akasaki, et al.			/
		5,122,845	06/1992	Manabe, et al.			/
		6,307,219	10/2001	Oku, et al.			/
		5,633,192	05/1997	Moustakas, et al.			/
		6,501,154	12/2002	Morita, et al.			/
DV		5,122,845	06/1992	Manabe, et al.			/

  

FOREIGN PATENT DOCUMENTS								
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
DV		05-86646	12/1993	Japan				
DV		05-063236	03/1993	Japan				
DV		60-173829	09/1985	Japan				

  

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)		
DV		Uchida, et al., "CHARACTERIZATION OF NITRIDATED LAYERS AND THEIR EFFECT ON THE GROWTH AND QUALITY OF GaN", Solid-State Electronics, Vol. 41, No. 2, (1997), pp. 135-139
DV		Patent Abstracts of Japan 60-173829 dated September 7, 1985

  

EXAMINER <i>Shibata</i>	DATE CONSIDERED <i>12/06/04</i>
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

